

**Search Notes**

Application/Control No.

10/816,622

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

OOTSU ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
216	7	6/7/2006	BT
216	11	6/7/2006	BT
216	24	6/7/2006	BT
216	96	6/7/2006	BT

**INTERFERENCE SEARCHED**

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216	7	6/7/2006	BT
216	11	6/7/2006	BT
216	24	6/7/2006	BT
216/96		6/7/2006	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	6/7/2006	BT